

Title (en)
SCANNING MICROSCOPE AND METHOD FOR DETERMINING THE POINT SPREAD FUNCTION (PSF) OF A SCANNING MICROSCOPE

Title (de)
SCANMIKROSKOP UND VERFAHREN ZUM BESTIMMUNG DER PUNKT-SPREIZ-FUNKTION (PSF) EINES SCANMIKROSKOPS

Title (fr)
MICROSCOPE À BALAYAGE ET PROCÉDÉ DE DÉTERMINATION DE LA FONCTION D'ÉTALEMENT PONCTUEL D'UN MICROSCOPE À BALAYAGE

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Application
EP 14783823 A 20141010

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Abstract (en)
[origin: WO2015055534A1] The invention relates to a method for operating a scanning microscope and for determining point spread functions with which sample images are recorded by the scanning microscope. In such a method it is provided that a sample is scanned by at least one illumination light beam, that at least one sample image is recorded by a detector device of the scanning microscope during the scanning by the illumination light beam, and that the point spread function with which a sample image is recorded by the scanning microscope is calculated from the at least one sample image. Use is made of a detector device having receiving elements, the distance between which is smaller than a diffraction disk that generates a sample point on the detector device. Detector signals generated by means of the receiving elements are in each case read out for different positions of the illumination light beam on the sample, as a result of which, by means of the scanning of the sample, the detector signals read out yield a plurality of sample images. The point spread functions with respect to the different detector signals are defined here in each case by means of an illumination point spread function and a detection point spread function. With respect to all the detector signals, a matching illumination point spread function is assumed which is shifted in accordance with the scanning movement for different detector signals. In addition, with respect to all the detector signals, a matching detection point spread function is assumed which takes account of a spatial offset between the detector elements. The plurality of sample images are used to calculate the illumination point spread function and the detection point spread function, and these are used to calculate the point spread functions with respect to the different detector signals. The invention further relates to a corresponding scanning microscope.

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